

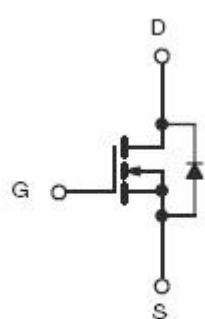
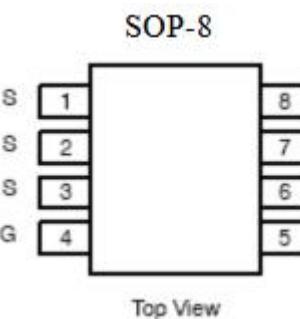
## 1. Features

- Advanced trench process technology
- High density cell design for ultra low on-resistance
- Fully characterized avalanche voltage and current

## 2. Applications

- $V_{ds}=30V$
- $R_{DS(ON)}=8.0\text{m}\Omega(\text{typ.}), V_{GS}@10V, I_{ds}@12A$
- $R_{DS(ON)}=11.5\text{m}\Omega(\text{typ.}), V_{GS}@4.5V, I_{ds}@6A$

## 3. Pin configuration



| Pin     | Function |
|---------|----------|
| 1,2,3   | Source   |
| 4       | Gate     |
| 5,6,7,8 | Drain    |

## 4. Maximum ratings and thermal characteristics

(Ta=25°C,unless otherwise notes)

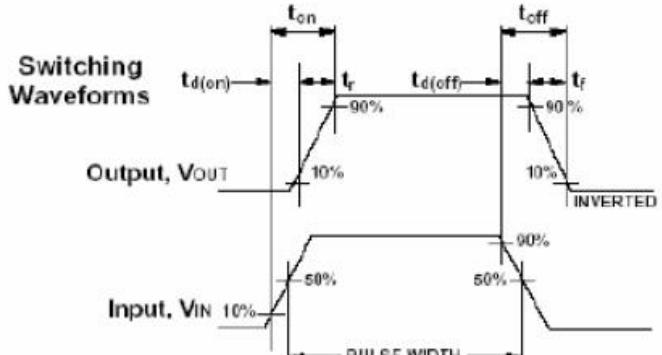
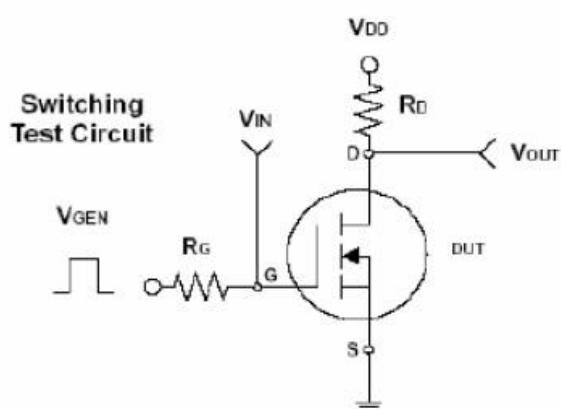
| Rating   | Symbol                           | Value          | Unit |   |
|--|----------------------------------|----------------|------|---|
| Drain-source voltage   | V <sub>DS</sub>                  | 30             | V    |   |
| Gate-source voltage  | V <sub>GS</sub>                  | ±20            | V    |   |
| Continuous drain current   | I <sub>D</sub>                   | 12             | A    |   |
| Pulsed drain current <sup>1)</sup>                               | I <sub>DM</sub>                  | 48             | A    |   |
| Maximum power dissipation  | T <sub>A</sub> =25°C             | P <sub>D</sub> | 3.1  | W |
|  | T <sub>A</sub> =75°C             | P <sub>D</sub> | 2.0  | W |
| Operating junction and storage temperature range                 | T <sub>J</sub> /T <sub>STG</sub> | -55 to 150     | °C   |   |
| Junction-to-case thermal resistance                              | R <sub>θJC</sub>                 | 40.3           | °C/W |   |
| Junction-to ambient thermal resistance (PCB mount) <sup>2)</sup> | R <sub>θJA</sub>                 | 59             | °C/W |   |

Note:Repetitive rating:pulse width limited by the maximum junction temperature

## 5. Ordering information

| Part number | Package |
|-------------|---------|
| KNE6303A    | SOP-8   |

## 6. Typical application circuit



## 7. Electrical characteristics

(Ta=25°C,unless otherwise notes)

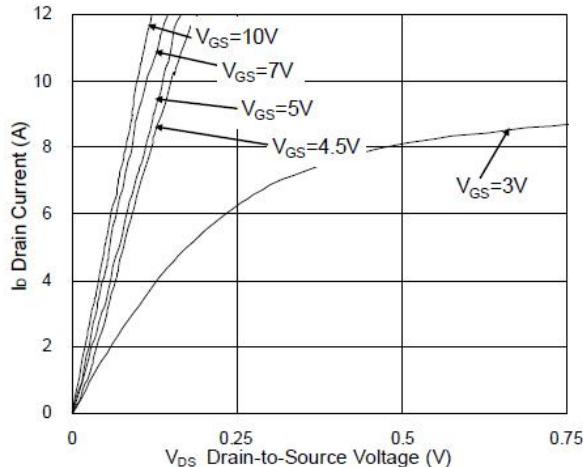
| Parameter                            | Symbol              | Test conditions  | Min. | Typ. | Max. | Units |
|--------------------------------------|---------------------|--|------|------|------|-------|
| <b>Static</b>                        |                     |  |      |      |      |       |
| Drain-source breakdown voltage       | BV <sub>DSS</sub>   | V <sub>GS</sub> =0V,I <sub>D</sub> =250μA  | 30   | -    | -    | V     |
| Drain-source on-state<br>rasistancem | R <sub>DS(ON)</sub> | V <sub>GS</sub> =4.5V,I <sub>D</sub> =6A   | -    | 11.5 | 14.0 | mΩ    |
|                                      |                     | V <sub>GS</sub> =10V,I <sub>D</sub> =12A   | -    | 8.0  | 10.0 | mΩ    |
| Gate threshold voltage               | V <sub>GS(th)</sub> | V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =-250μA   | 1    | 1.8  | 3    | V     |
| Forward transconductance             | G <sub>fs</sub>     | V <sub>DS</sub> =15V,I <sub>D</sub> =6A  | -    | 12   | -    | S     |
| Zero gate voltage drain current      | I <sub>DSS</sub>    | V <sub>DS</sub> =25V,V <sub>GS</sub> =0V   | -    | -    | 1    | μA    |
| Gate-source forward leakage          | I <sub>GSS</sub>    | V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V  | -    | -    | ±100 | nA    |
| <b>Dynamic<sup>3)</sup></b>          |                     |  |      |      |      |       |
| Total gate charge                    | Q <sub>g</sub>      | I <sub>D</sub> =35A<br>V <sub>DS</sub> =15V<br>V <sub>GS</sub> =10V  | -    | 10   |      | nC    |
| Gate-source charge                   | Q <sub>gs</sub>     |  |      | 3.5  |      | nC    |
| Gate-drain (“miller”)charge          | Q <sub>gd</sub>     |  | -    | 3    |      | nC    |
| Turn-on delay time                   | t <sub>d(off)</sub> | V <sub>DD</sub> =15V<br>I <sub>D</sub> =1A<br>R <sub>G</sub> =6Ω<br>R <sub>L</sub> =15Ω<br>V <sub>GEN</sub> =10V | -    | 12   | -    | ns    |
| Rise time                            | t <sub>r</sub>      |  | -    | 4    | -    | ns    |
| Turn-off delay time                  | t <sub>d(off)</sub> |  | -    | 32   | -    | ns    |
| Fall time                            | t <sub>f</sub>      |  | -    | 6    | -    | ns    |
| Input capacitance                    | C <sub>iss</sub>    | V <sub>GS</sub> =0V<br>V <sub>DS</sub> =15V<br>f=1.0MHz  | -    | 1300 | -    | pF    |
| Output capacitance                   | C <sub>oss</sub>    |  | -    | 270  | -    | pF    |
| Reverse transfer capacitance         | C <sub>rss</sub>    |  | -    | 145  | -    | pF    |

### Source-drain diode

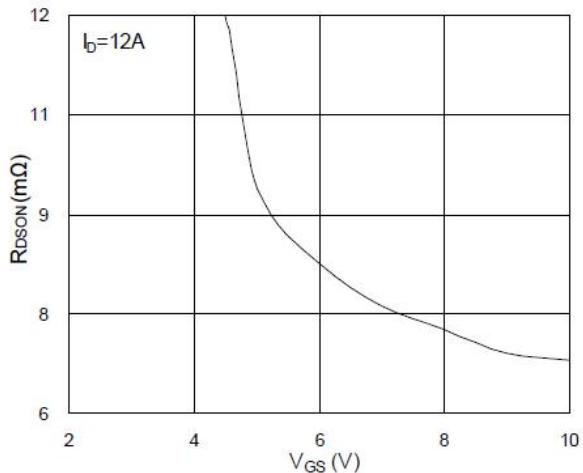
| Parameter                 | Symbol          | Test condition                          | Min. | Typ. | Max. | Units |
|---------------------------|-----------------|---|------|------|------|-------|
| Diode forward voltage     | V <sub>SD</sub> | I <sub>s</sub> =10A,V <sub>GS</sub> =0V | -    | 0.87 | 1.5  | V     |
| Max.diode forward current | I <sub>s</sub>  |   | -    | -    | 12   | A     |

Notes:Pulse width≤300μs,duty cycle≤2%

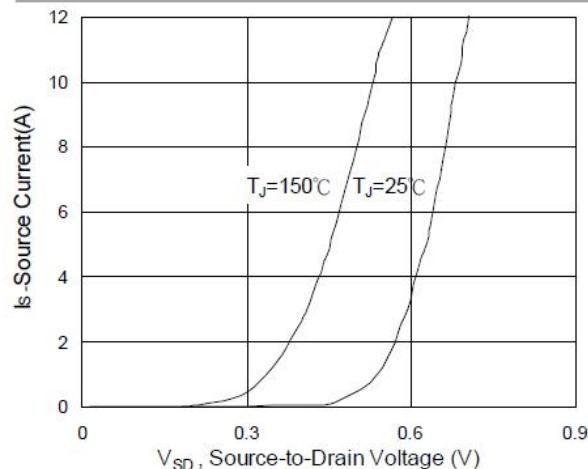
## 8. Test circuits and waveforms



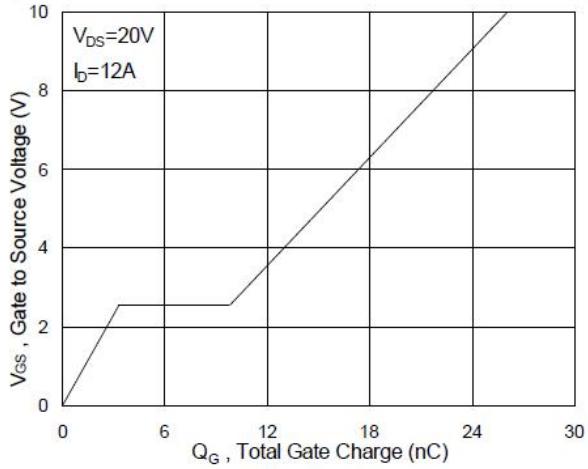
**Fig.1 Typical Output Characteristics**



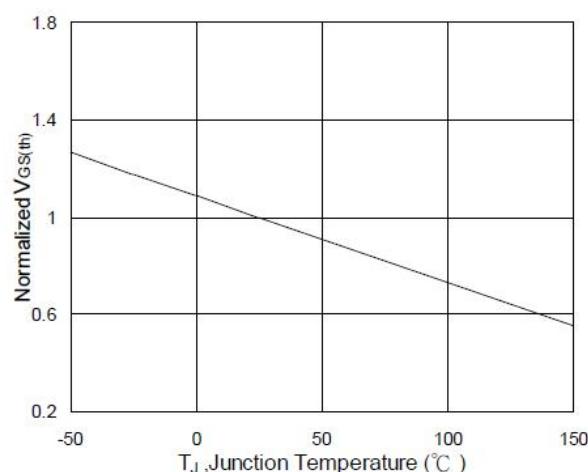
**Fig.2 On-Resistance vs. G-S Voltage**



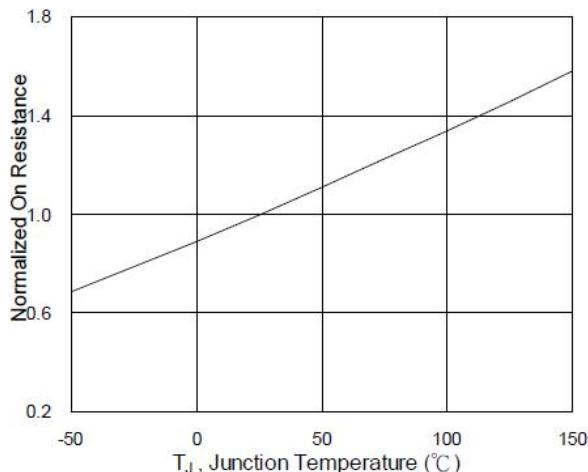
**Fig.3 Forward Characteristics of Reverse**



**Fig.4 Gate-Charge Characteristics**



**Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$**



**Fig.6 Normalized  $R_{DS(on)}$  vs.  $T_J$**

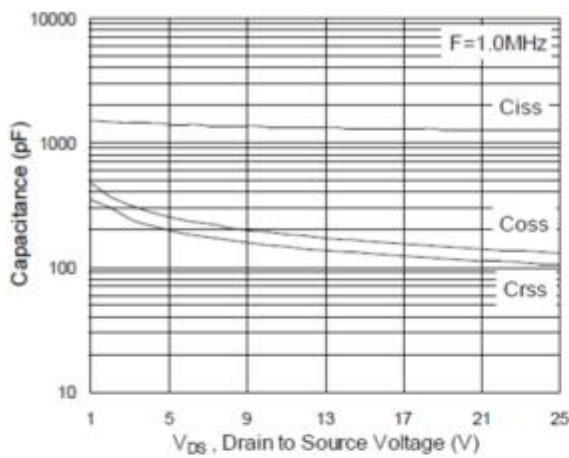


Fig.7 Capacitance

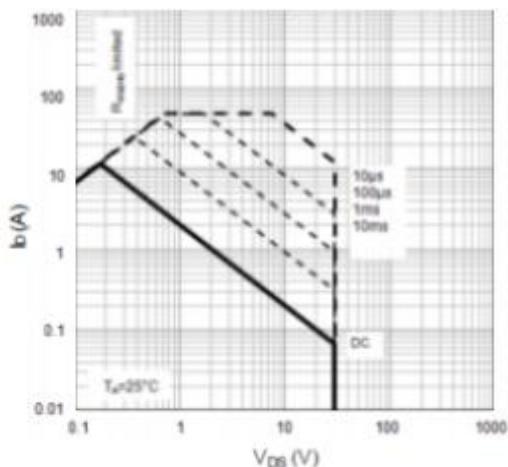


Fig.8 Safe Operating Area

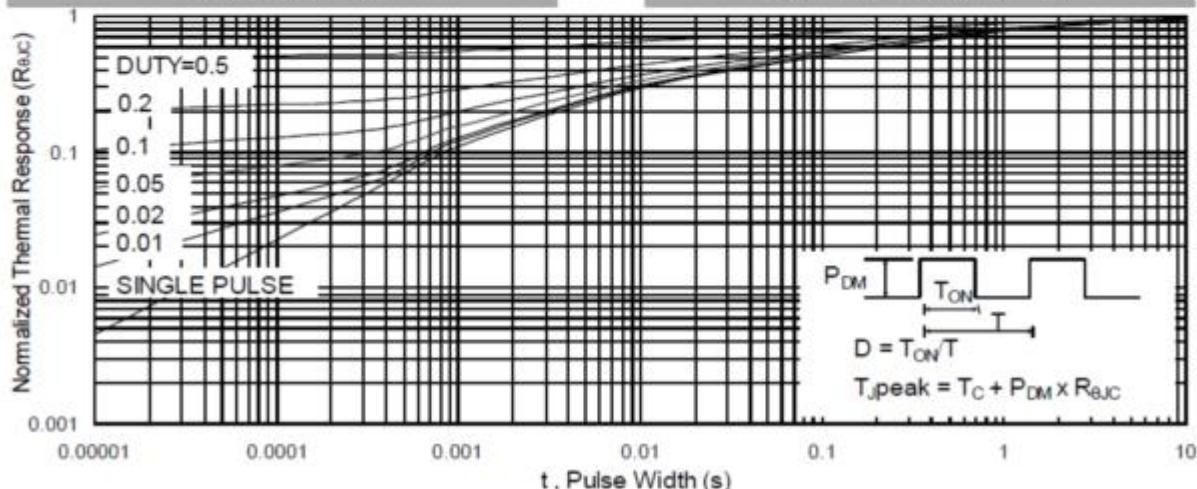


Fig.9 Normalized Maximum Transient Thermal Impedance

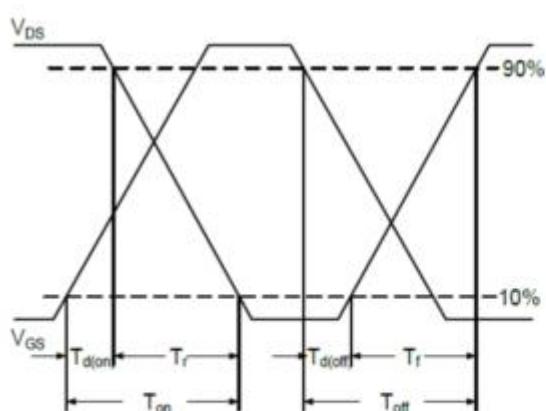


Fig.10 Switching Time Waveform

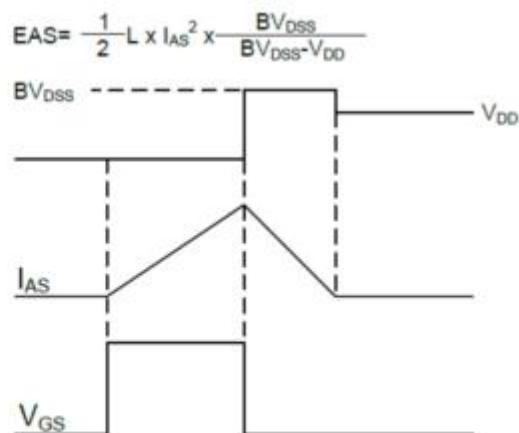


Fig.11 Unclamped Inductive Switching Waveform